

SIPMOS® Small-Signal-Transistor

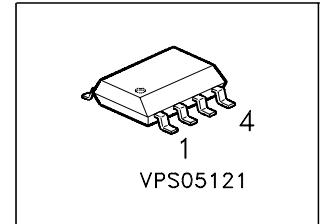
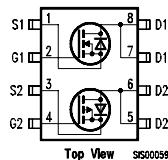
Features

- Dual N- and P -Channel
- Enhancement mode
- Avalanche rated
- dv/dt rated

Product Summary

	N	P	
Drain source voltage	V_{DS}	60	-60
Drain-Source on-state resistance	$R_{DS(on)}$	0.12	0.3
Continuous drain current	I_D	3	-2

Type	Package	Ordering Code
BSO 612 CV	SO 8	Q67041-S4015



Maximum Ratings, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Value		Unit
		N	P	
Continuous drain current $T_A = 25^\circ\text{C}$	I_D	3	-2	A
$T_A = 70^\circ\text{C}$				
Pulsed drain current $T_A = 25^\circ\text{C}$	$I_{D \text{ puls}}$	12	-8	
Avalanche energy, single pulse $I_D = 3 \text{ A}, V_{DD} = 25 \text{ V}, R_{GS} = 25 \Omega$ $I_D = -2 \text{ A}, V_{DD} = -25 \text{ V}, R_{GS} = 25 \Omega$	E_{AS}	47	-	mJ
Avalanche energy, periodic limited by $T_{j\max}$	E_{AR}	0.2	0.2	
Reverse diode dv/dt, $T_{j\max} = 150^\circ\text{C}$ $I_S = 3 \text{ A}, V_{DS} = 48 \text{ V}, di/dt = 200 \text{ A}/\mu\text{s}$ $I_S = -2 \text{ A}, V_{DS} = -48 \text{ V}, di/dt = -200 \text{ A}/\mu\text{s}$	dv/dt	6	-	kV/ μ s
Gate source voltage	V_{GS}	± 20	± 20	V
Power dissipation $T_A = 25^\circ\text{C}$	P_{tot}	2	2	W
Operating and storage temperature	T_j, T_{stg}	$-55...+150$		°C
IEC climatic category; DIN IEC 68-1		55/150/56		

Termal Characteristics

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

Dynamic Characteristics

Thermal resistance, junction - soldering point (Pin 4)	N P	R_{thJS}	-	-	40	K/W
SMD version, device on PCB: @ min. footprint; $t \leq 10$ sec.	N	R_{thJA}	-	-	110	
@ 6 cm ² cooling area ¹⁾ ; $t \leq 10$ sec.	N		-	-	62.5	
@ min. footprint; $t \leq 10$ sec.	P		-	-	70	
@ 6 cm ² cooling area ¹⁾ ; $t \leq 10$ sec.	P		-	-	62.5	

Static Characteristics, at $T_j = 25$ °C, unless otherwise specified

Drain- source breakdown voltage $V_{GS} = 0$ V, $I_D = 250$ µA $V_{GS} = 0$ V, $I_D = -250$ µA	N P	$V_{(BR)DSS}$	60 -60	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 20$ µA $I_D = -450$ µA	N P	$V_{GS(th)}$	2.1 -2.1	3 -3	4 -4	
Zero gate voltage drain current $V_{DS} = 60$ V, $V_{GS} = 0$ V, $T_j = 25$ °C $V_{DS} = 60$ V, $V_{GS} = 0$ V, $T_j = 125$ °C $V_{DS} = -60$ V, $V_{GS} = 0$ V, $T_j = 25$ °C $V_{DS} = -60$ V, $V_{GS} = 0$ V, $T_j = 125$ °C	N N P P	I_{DSS}	- - - -	0.1 10 -0.1 -10	1 100 -1 -100	µA
Gate-source leakage current $V_{GS} = 20$ V, $V_{DS} = 0$ V $V_{GS} = -20$ V, $V_{DS} = 0$ V	N P	I_{GSS}	- -	10 -10	100 -100	nA
Drain-Source on-state resistance $V_{GS} = 10$ V, $I_D = 3$ A $V_{GS} = -10$ V, $I_D = -2$ A	N P	$R_{DS(on)}$	- -	0.09 0.22	0.12 0.3	Ω

¹Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical without blown air.

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

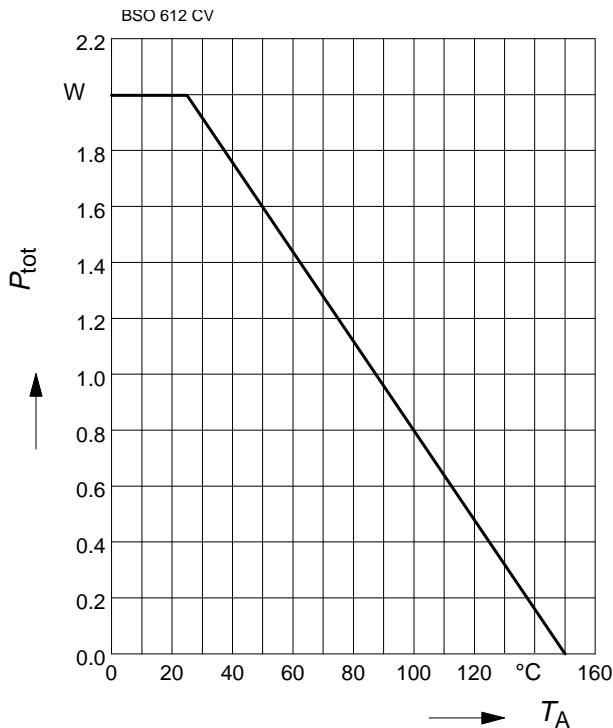
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Characteristics					
Transconductance $V_{DS} \geq 2 * I_D * R_{DS(on)max}, I_D = 3 \text{ A}$ $V_{DS} \geq 2 * I_D * R_{DS(on)max}, I_D = -2 \text{ A}$	N P	g_{fs}	2 1.2	4 2.4	- -
Input capacitance $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$ $V_{GS} = 0 \text{ V}, V_{DS} = -25 \text{ V}, f = 1 \text{ MHz}$	N P	C_{iss}	- -	275 320	340 400
Output capacitance $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$ $V_{GS} = 0 \text{ V}, V_{DS} = -25 \text{ V}, f = 1 \text{ MHz}$	N P	C_{oss}	- -	90 105	115 130
Reverse transfer capacitance $V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$ $V_{GS} = 0 \text{ V}, V_{DS} = -25 \text{ V}, f = 1 \text{ MHz}$	N P	C_{rss}	- -	50 40	65 50
Turn-on delay time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}, R_G = 33 \Omega$ $V_{DD} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -2 \text{ A}, R_G = 27 \Omega$	N P	$t_{d(on)}$	- -	12 15	18 23
Rise time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}, R_G = 33 \Omega$ $V_{DD} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -2 \text{ A}, R_G = 27 \Omega$	N P	t_r	- -	35 60	55 90
Turn-off delay time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}, R_G = 33 \Omega$ $V_{DD} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -2 \text{ A}, R_G = 27 \Omega$	N P	$t_{d(off)}$	- -	25 145	40 220
Fall time $V_{DD} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}, R_G = 33 \Omega$ $V_{DD} = -30 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -2 \text{ A}, R_G = 27 \Omega$	N P	t_f	- -	30 95	45 140

Electrical Characteristics, at $T_j = 25^\circ\text{C}$, unless otherwise specified

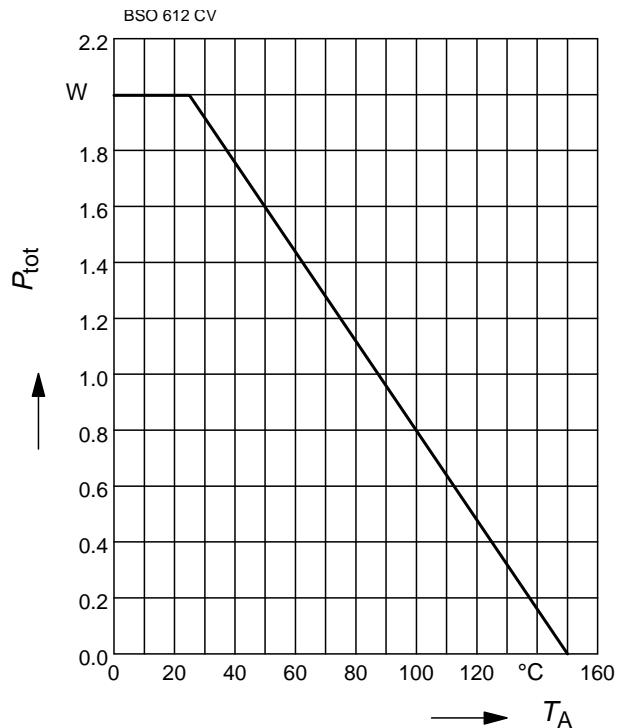
Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Characteristics					
Gate to source charge $V_{DD} = 48 \text{ V}, I_D = 3 \text{ A}$ $V_{DD} = -48 \text{ V}, I_D = -2 \text{ A}$	N P	Q_{gs}	- -	1 2	1.5 3
Gate to drain charge $V_{DD} = 48 \text{ V}, I_D = 3 \text{ A}$ $V_{DD} = -48 \text{ V}, I_D = -2 \text{ A}$	N P	Q_{gd}	- -	5.5 4.5	8.3 6.8
Gate charge total $V_{DD} = 48 \text{ V}, I_D = 3 \text{ A}, V_{GS} = 0 \text{ to } 10\text{V}$ $V_{DD} = -48 \text{ V}, I_D = -2 \text{ A}, V_{GS} = 0 \text{ to } -10\text{V}$	N P	Q_g	- -	10.3 10.5	15.5 16
Gate plateau voltage $V_{DD} = 48 \text{ V}, I_D = 3 \text{ A}$ $V_{DD} = -48 \text{ V}, I_D = -2 \text{ A}$	N P	$V_{(\text{plateau})}$	- -	5 -4	- -
Reverse Diode					
Inverse diode continuous forward current $T_A = 25^\circ\text{C}$	N P	I_S	- -	- -	3 -2
Inverse diode direct current,pulsed $T_A = 25^\circ\text{C}$	N P	I_{SM}	- -	- -	12 -8
Inverse diode forward voltage $V_{GS} = 0 \text{ V}, I_F = I_S$ $V_{GS} = 0 \text{ V}, I_F = I_S$	N P	V_{SD}	- -	0.9 -0.9	1.2 -1.2
Reverse recovery time $V_R = 30 \text{ V}, I_F = I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$ $V_R = -30 \text{ V}, I_F = I_S, di_F/dt = -100 \text{ A}/\mu\text{s}$	N P	t_{rr}	- -	55 55	85 85
Reverse recovery charge $V_R = 30 \text{ V}, I_F = I_S, di_F/dt = 100 \text{ A}/\mu\text{s}$ $V_R = -30 \text{ V}, I_F = I_S, di_F/dt = -100 \text{ A}/\mu\text{s}$	N P	Q_{rr}	- -	90 65	135 100

Power Dissipation (N-Ch.)

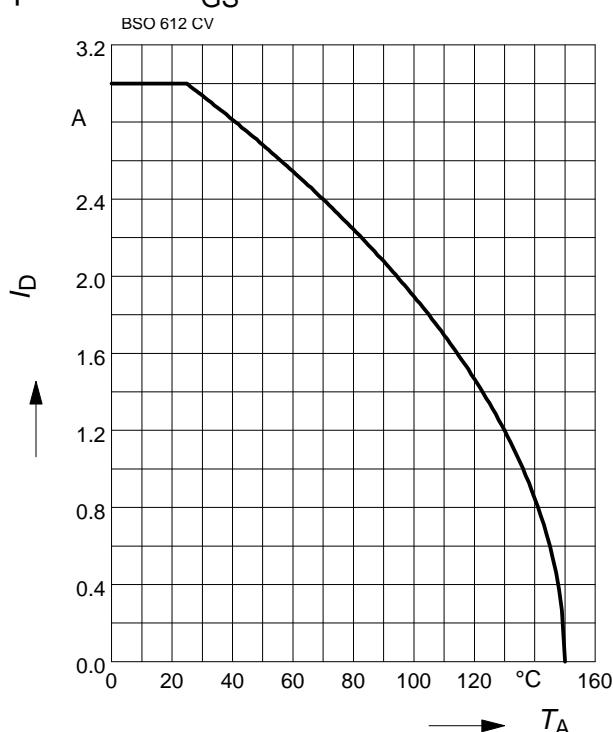
$$P_{\text{tot}} = f(T_A)$$


Power Dissipation (P-Ch.)

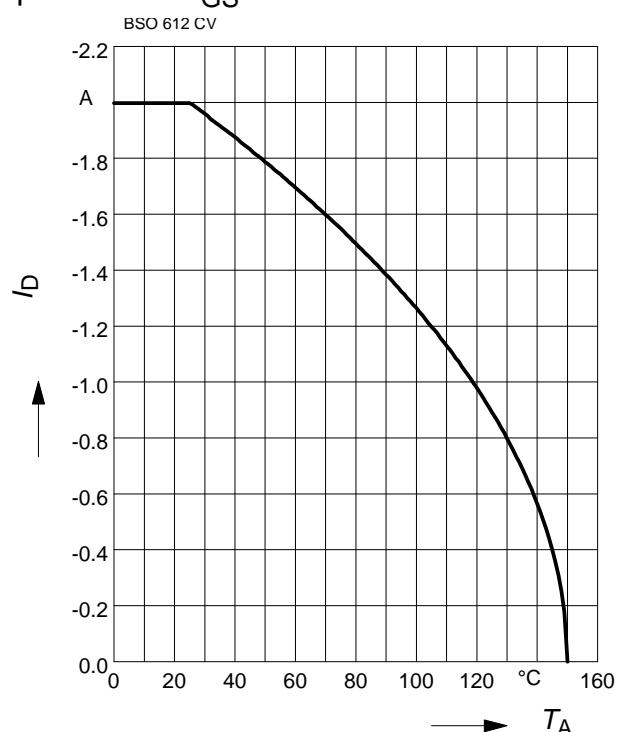
$$P_{\text{tot}} = f(T_A)$$


Drain current (N-Ch.)

$$I_D = f(T_A)$$

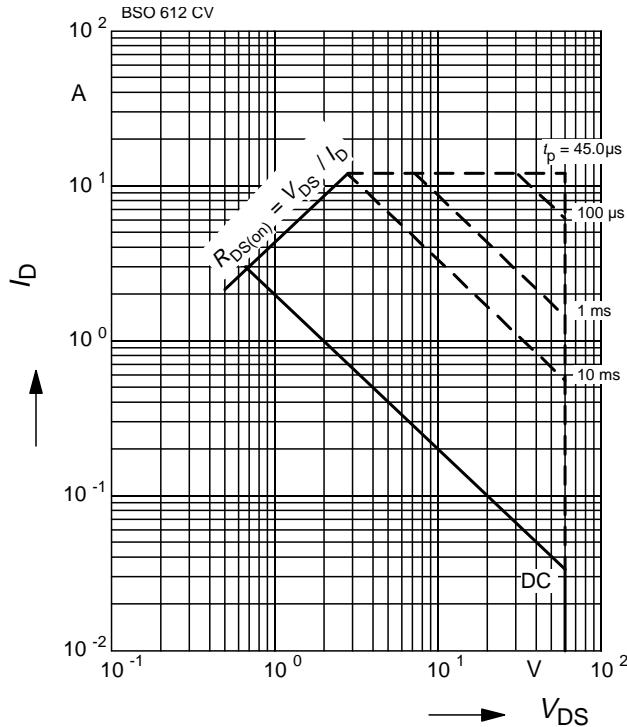
 parameter: $V_{GS} \geq 10$ V

Drain current (P-Ch.)

$$I_D = f(T_A)$$

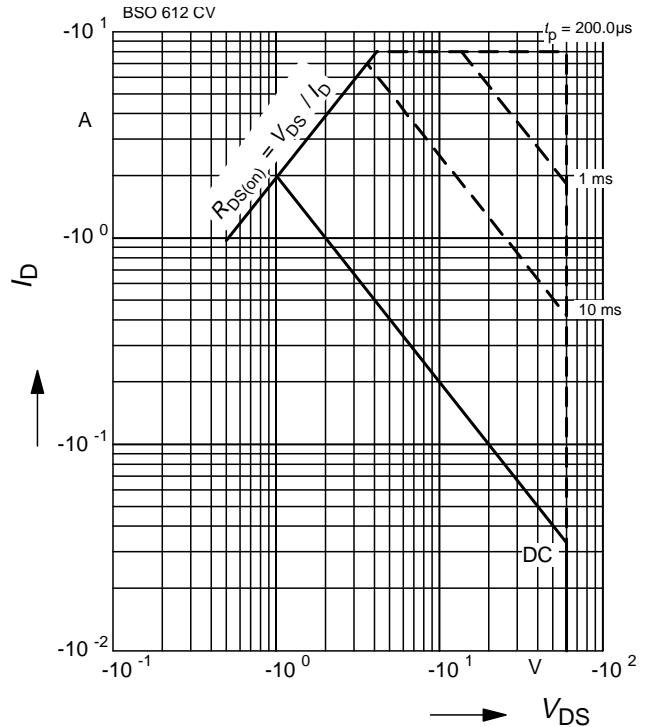
 parameter: $V_{GS} \geq -10$ V


Safe operating area (N-Ch.)

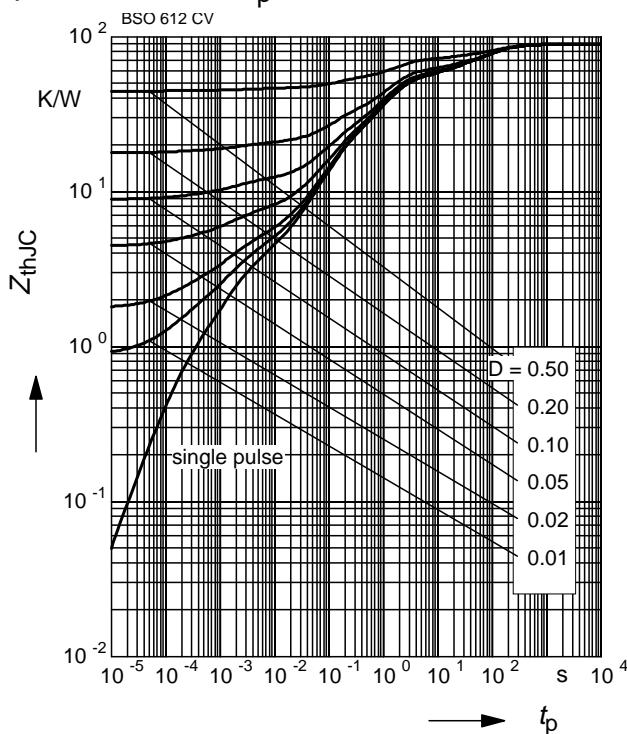
$$I_D = f(V_{DS})$$

 parameter : $D = 0$, $T_A = 25^\circ\text{C}$

Safe operating area (P-Ch.)

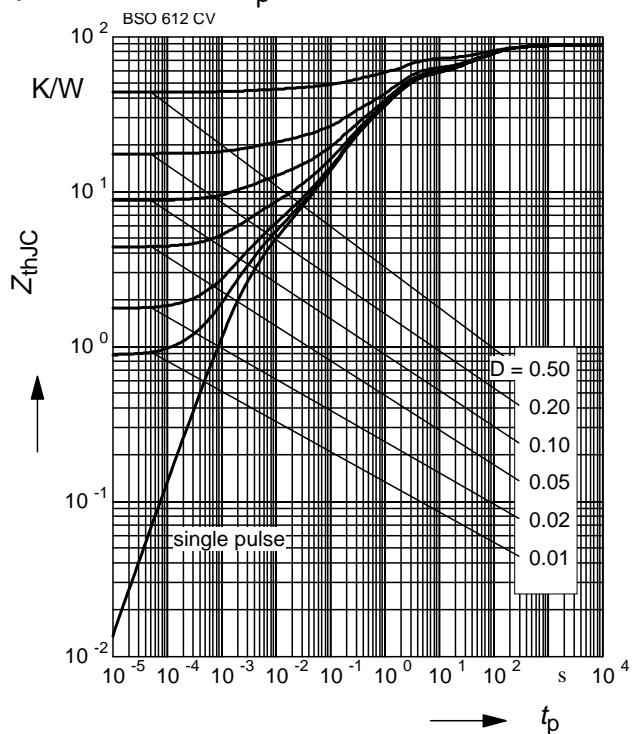
$$I_D = f(V_{DS})$$

 parameter : $D = 0$, $T_A = 25^\circ\text{C}$

Transient thermal impedance (N-Ch.)

$$Z_{\text{thJC}} = f(t_p)$$

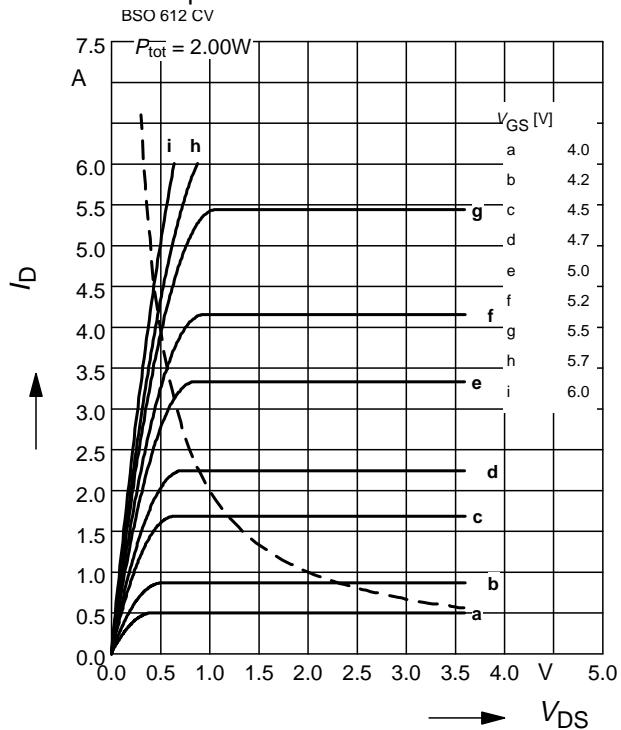
 parameter : $D = t_p/T$

Transient thermal impedance (P-Ch.)

$$Z_{\text{thJC}} = f(t_p)$$

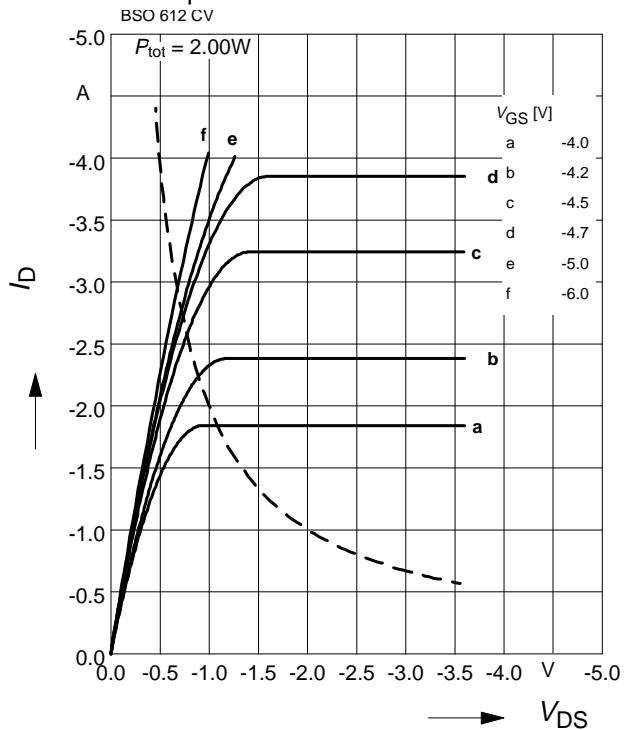
 parameter : $D = t_p/T$


Typ. output characteristics (N-Ch.)

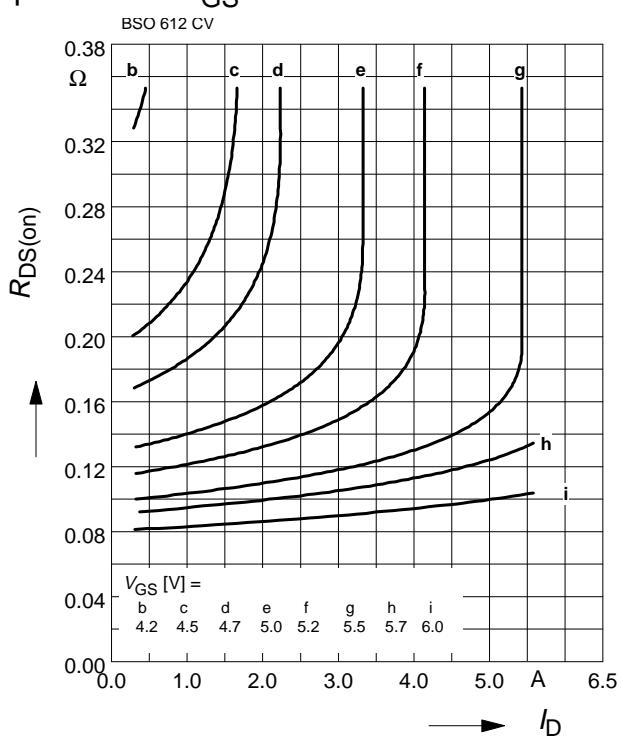
$$I_D = f(V_{DS})$$

 parameter: $t_p = 80 \mu\text{s}$

Typ. output characteristics (P-Ch.)

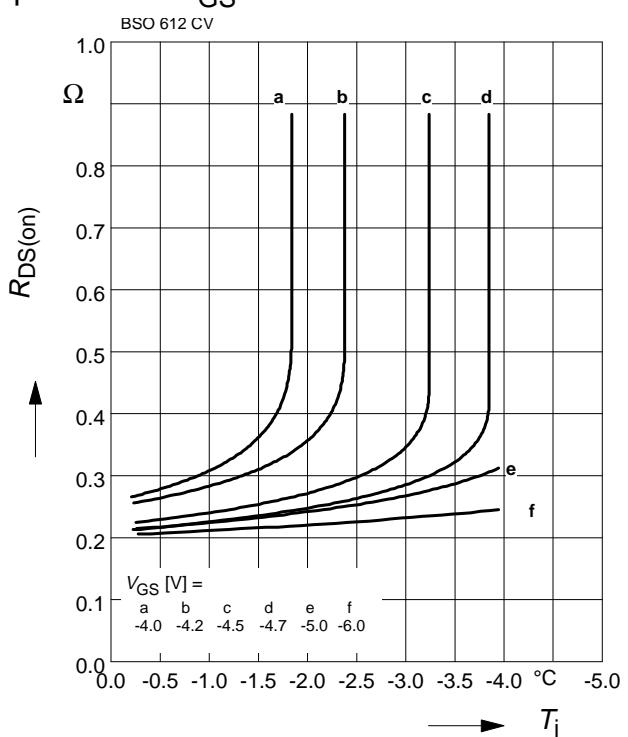
$$I_D = f(V_{DS})$$

 parameter: $t_p = 80 \mu\text{s}$

Typ. drain-source-on-resistance (N-Ch.)

$$R_{DS(\text{on})} = f(I_D)$$

 parameter: V_{GS}

Typ. drain-source-on-resistance (P-Ch.)

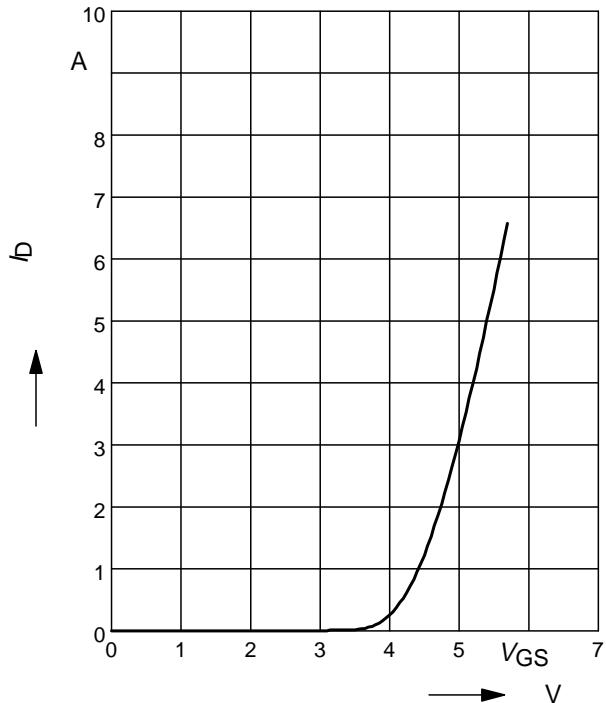
$$R_{DS(\text{on})} = f(I_D)$$

 parameter: V_{GS}


Typ. transfer characteristics (N-Ch.)

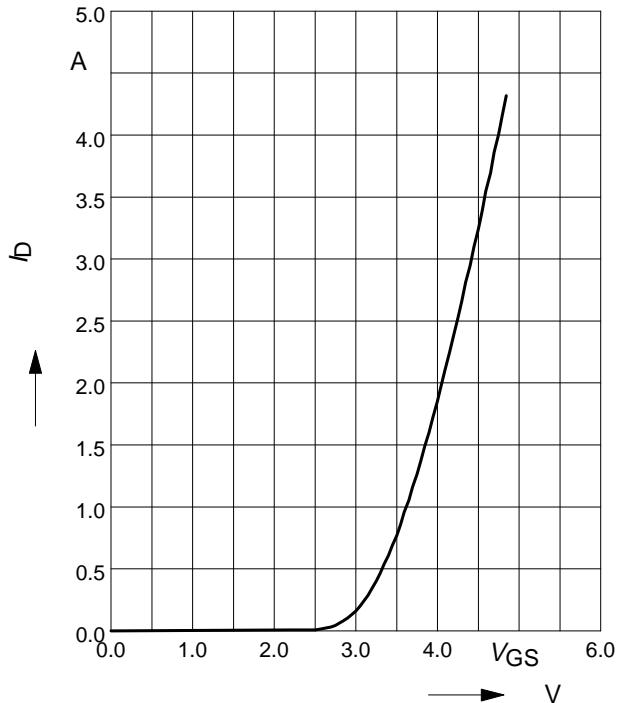
 parameter: $t_p = 80 \mu\text{s}$

$$I_D = f(V_{GS}), V_{DS} \geq 2 \times I_D \times R_{DS(\text{on})\max}$$

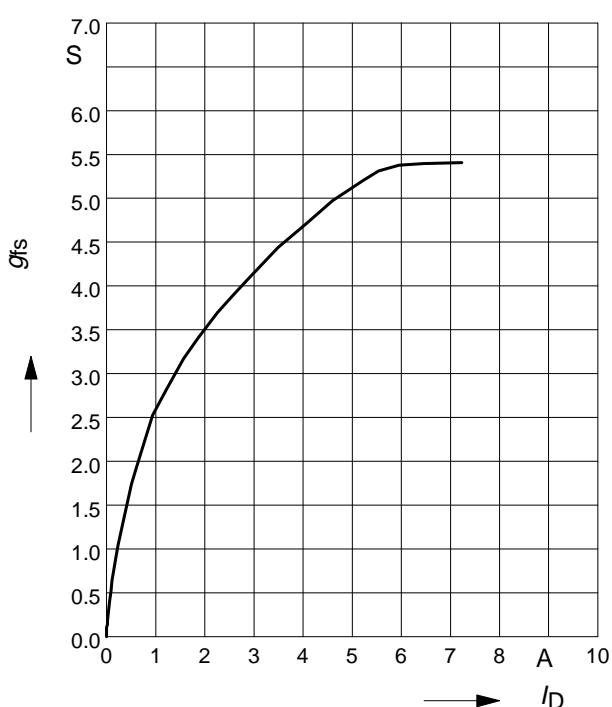

Typ. transfer characteristics (P-Ch.)

 parameter: $t_p = 80 \mu\text{s}$

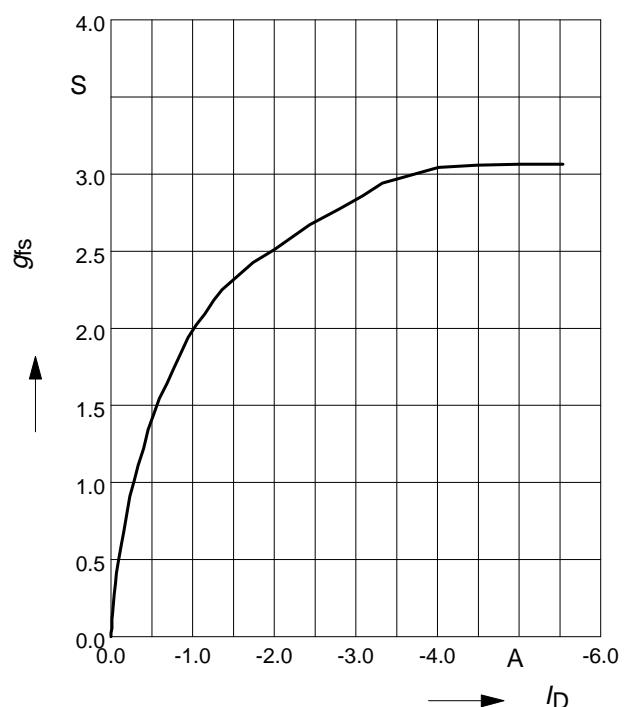
$$I_D = f(V_{GS}), V_{DS} \geq 2 \times I_D \times R_{DS(\text{on})\max}$$


Typ. forward transconductance (N-Ch.)

$$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$$

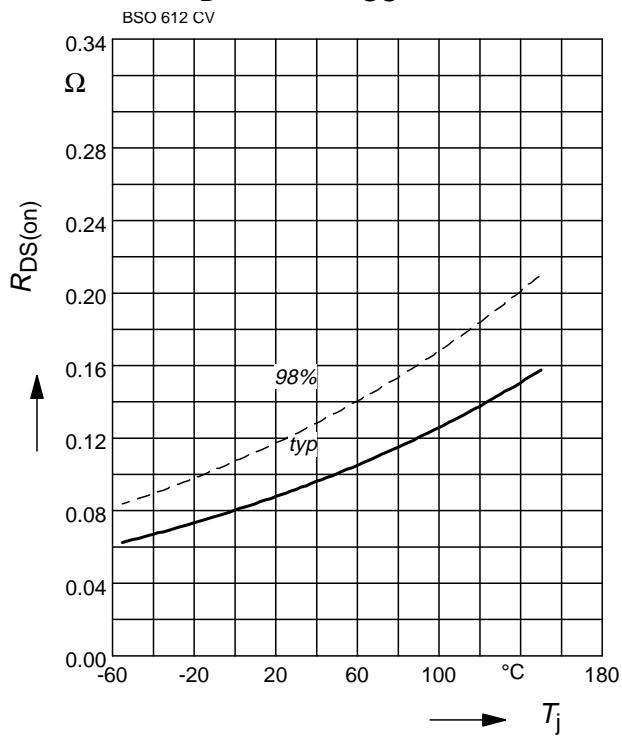
 parameter: g_{fs}

Typ. forward transconductance (P-Ch.)

$$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$$

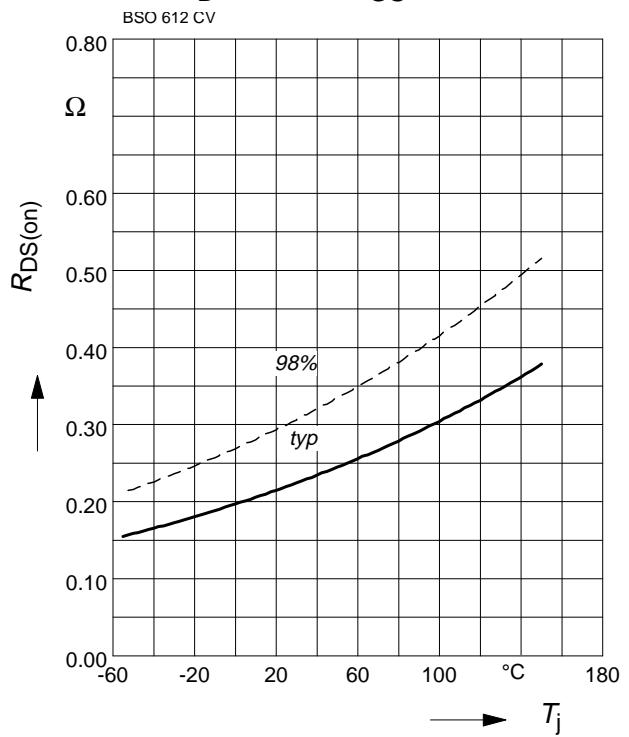
 parameter: g_{fs}


Drain-source on-resistance (N-Ch.)

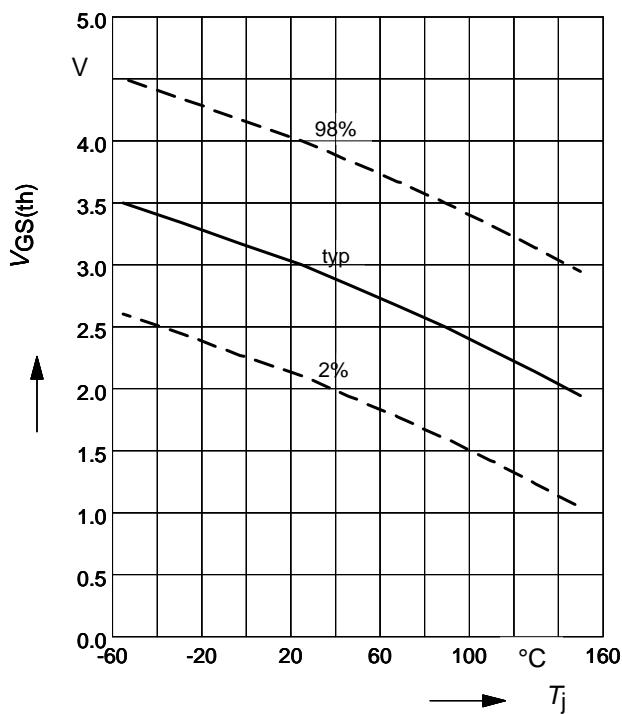
$$R_{DS(on)} = f(T_j)$$

 parameter : $I_D = 3 \text{ A}$, $V_{GS} = 10 \text{ V}$

Drain-source on-resistance (P-Ch.)

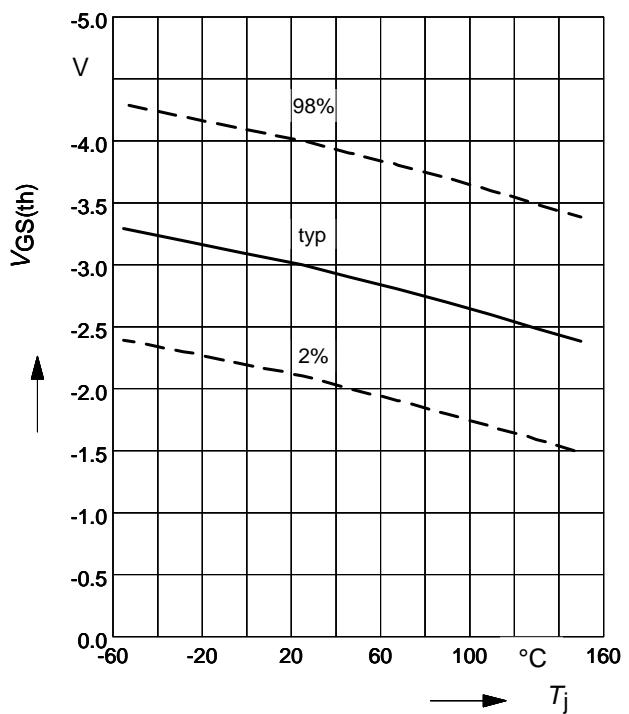
$$R_{DS(on)} = f(T_j)$$

 parameter : $I_D = -2 \text{ A}$, $V_{GS} = -10 \text{ V}$

Gate threshold voltage (N-Ch.)

$$V_{GS(th)} = f(T_j)$$

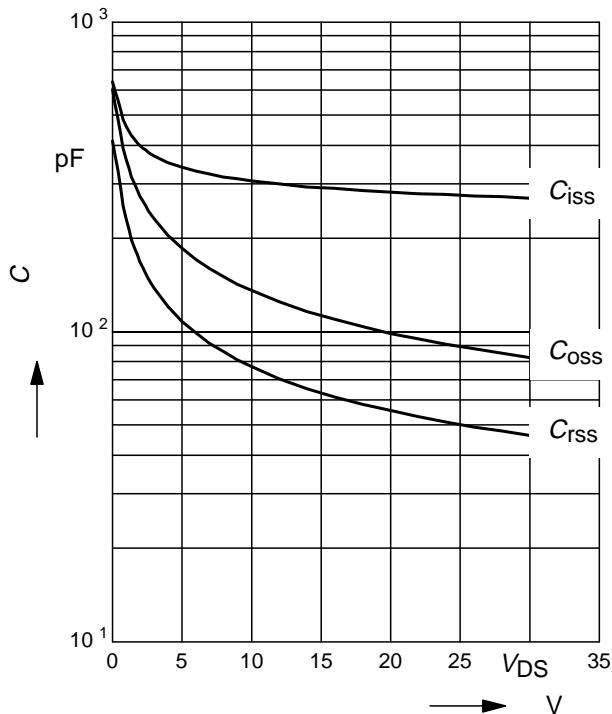
 parameter: $V_{GS} = V_{DS}$, $I_D = 20 \mu\text{A}$

Gate threshold voltage (P-Ch.)

$$V_{GS(th)} = f(T_j)$$

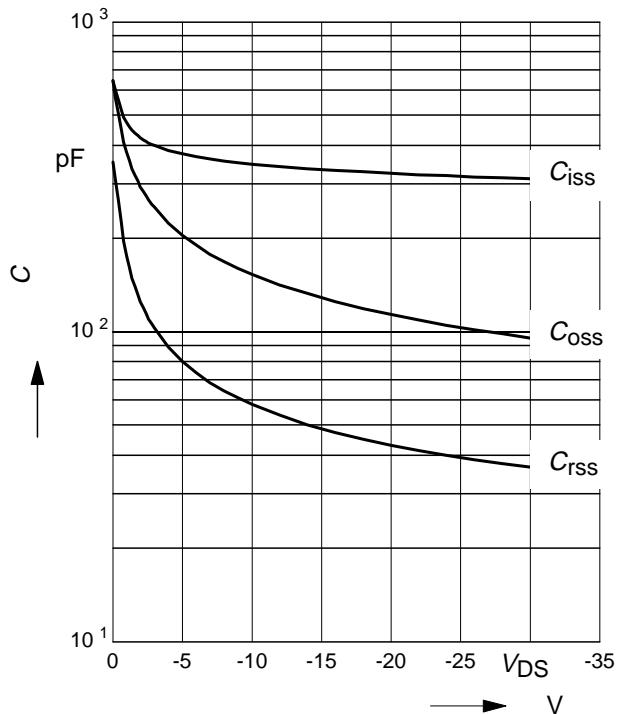
 parameter: $V_{GS} = V_{DS}$, $I_D = -450 \mu\text{A}$


Typ. capacitances (N-Ch.)

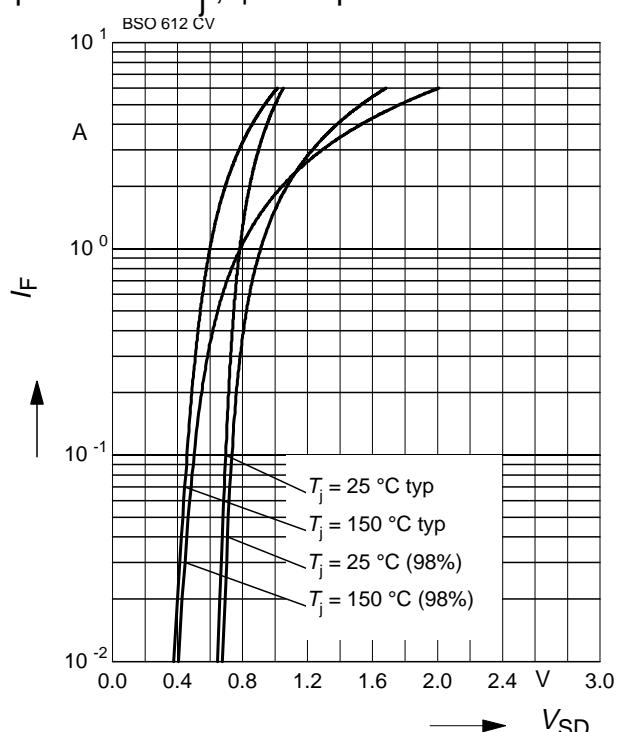
$$C = f(V_{DS})$$

 parameter: $V_{GS}=0$ V, $f=1$ MHz

Typ. capacitances (P-Ch.)

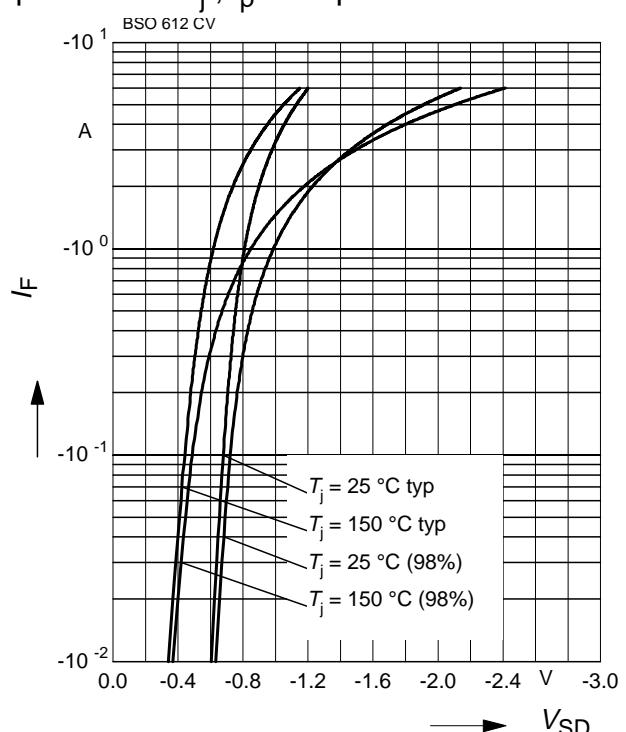
$$C = f(V_{DS})$$

 parameter: $V_{GS}=0$ V, $f=1$ MHz

Forward characteristics of reverse diode

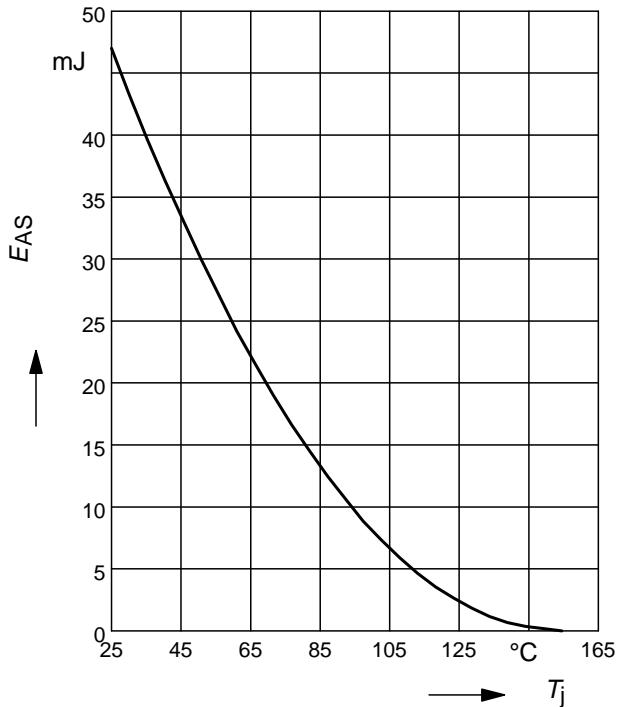
$$I_F = f(V_{SD}), (\text{N-Ch.})$$

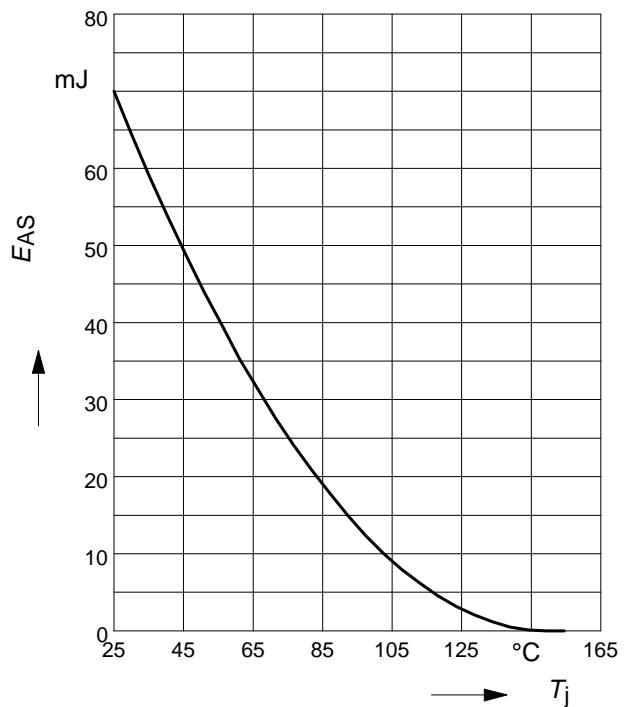
 parameter: T_j , $t_p = 80 \mu\text{s}$

Forward characteristics of reverse diode

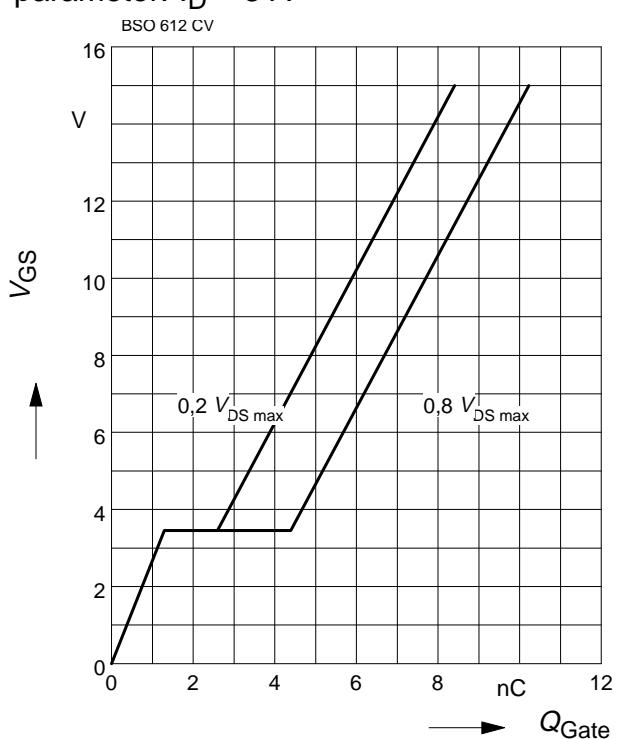
$$I_F = f(V_{SD}), (\text{P-Ch.})$$

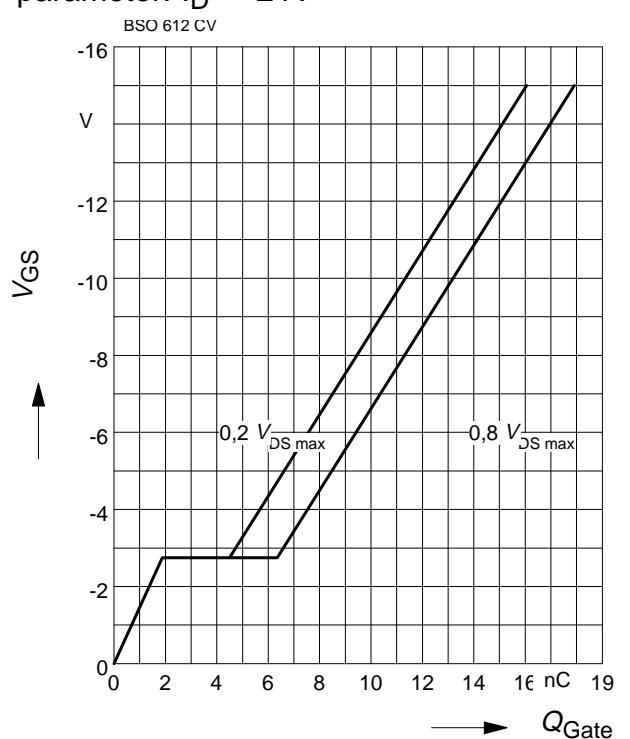
 parameter: T_j , $t_p = 80 \mu\text{s}$


Avalanche Energy $E_{AS} = f(T_j)$ (N-Ch.)

 parameter: $I_D = 3 \text{ A}$, $V_{DD} = 25 \text{ V}$
 $R_{GS} = 25 \Omega$

Avalanche Energy $E_{AS} = f(T_j)$

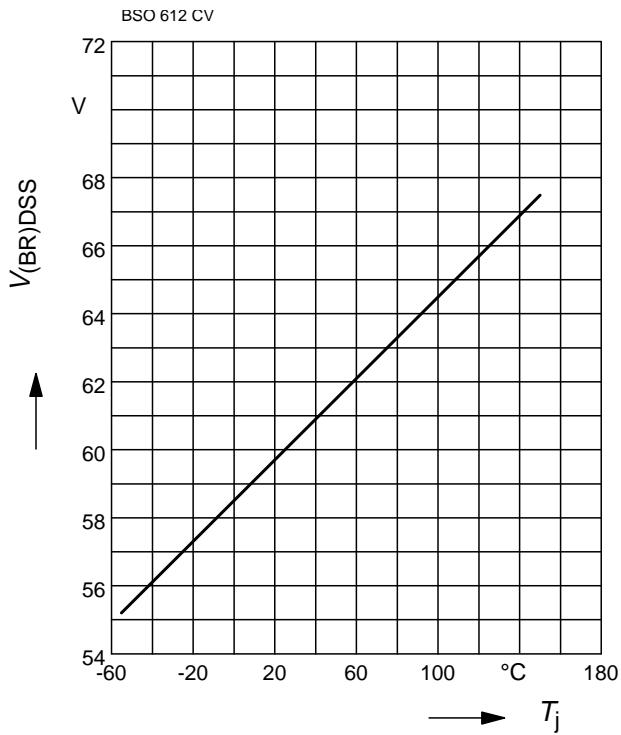
 parameter: $I_D = -2 \text{ A}$, $V_{DD} = -25 \text{ V}$
 $R_{GS} = 25 \Omega$

Typ. gate charge (N-Ch.)
 $V_{GS} = f(Q_{Gate})$

 parameter: $I_D = 3 \text{ A}$

Typ. gate charge (P-Ch.)
 $V_{GS} = f(Q_{Gate})$

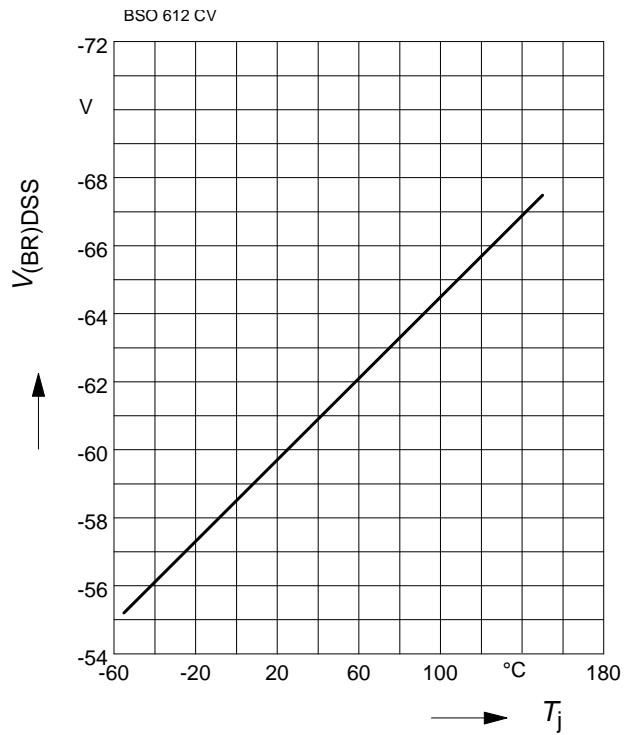
 parameter: $I_D = -2 \text{ A}$


Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j), \text{ (N-Ch.)}$$


Drain-source breakdown voltage

$$V_{(BR)DSS} = f(T_j), \text{ (P-Ch.)}$$



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